Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/743,747	SUNOHARA ET AL.	
Examiner	Art Unit	
John Kim	1723	

SEARCHED					
Class	Subclass	Date	Examiner		
210	321.6, 321.72, 321.78, 321.79	11/18/2005	JK		
	321.8				
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INTERFERENCE SEARCHED				
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DATE	EXMR JK
11/18/2005	JK
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